

Search Notes**Application/Control No.**

10/676,652

Examiner

Chase Peers

Applicant(s)/Patent under Reexamination

CHANG ET AL.

Art Unit

2186

SEARCHED

Class	Subclass	Date	Examiner
711	103,171, 202,203, 207,209	10/31/2005	CP
707	205	10/31/2005	CP
703	23	10/31/2005	CP
365	51	10/31/2005	CP

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched East for terms relating to mapping and wear leveling	10/31/2005	CP
Searched NPL for terms relating to mapping	10/31/2005	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner